

Supply Chain Hardware Integrity for Electronics Defense (SHIELD)

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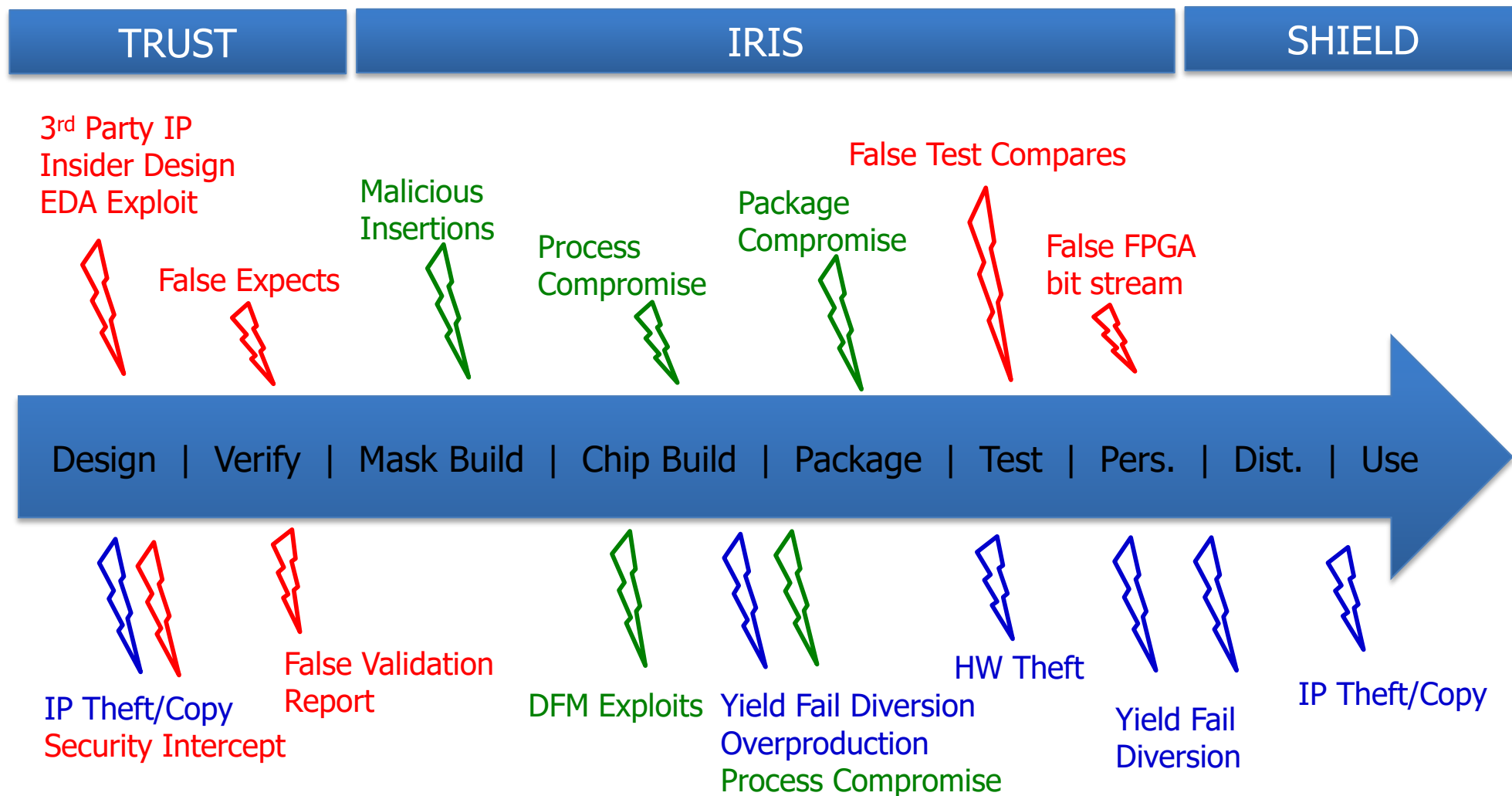


Threats to Integrated Circuit Integrity



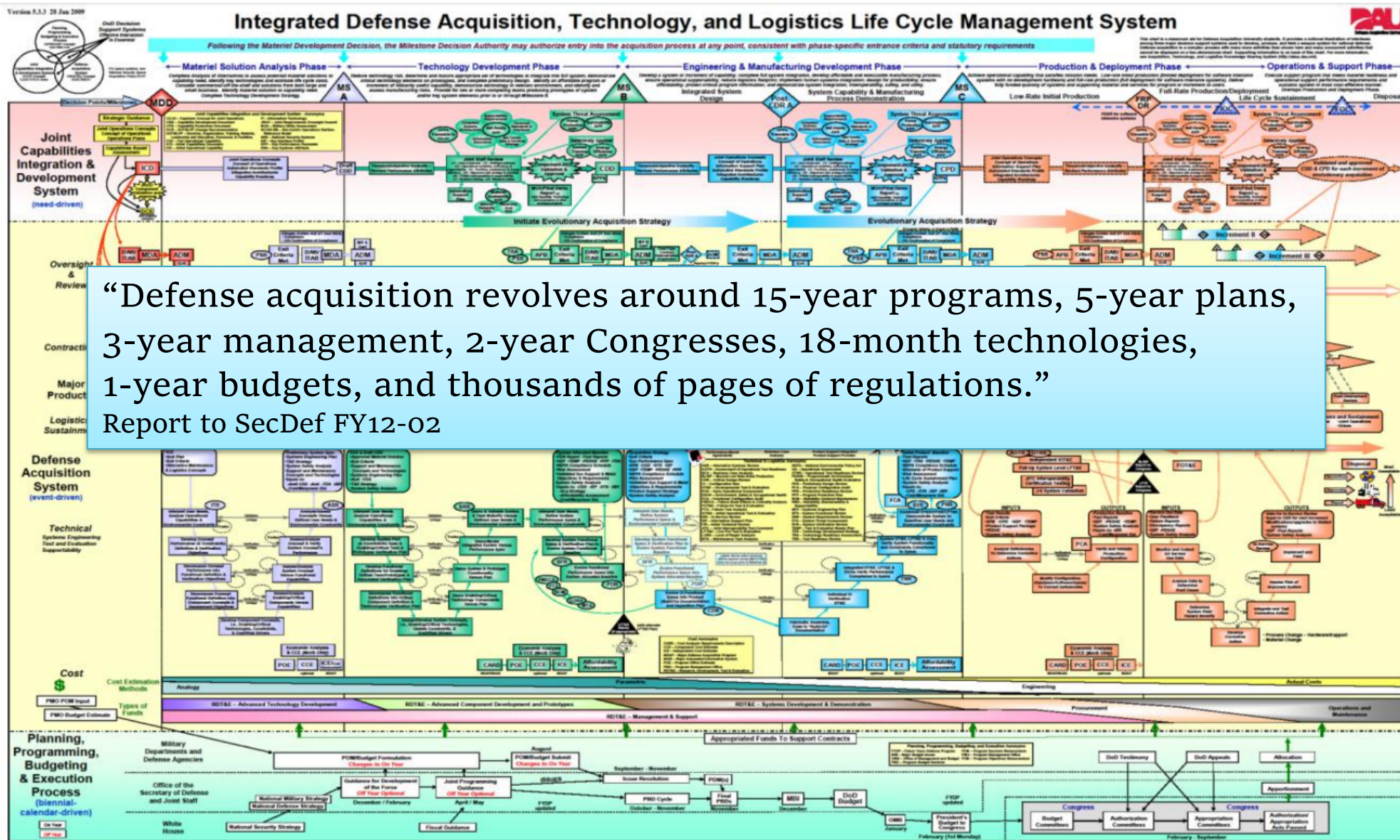
Threats to integrated circuit integrity

DARPA mitigation technologies



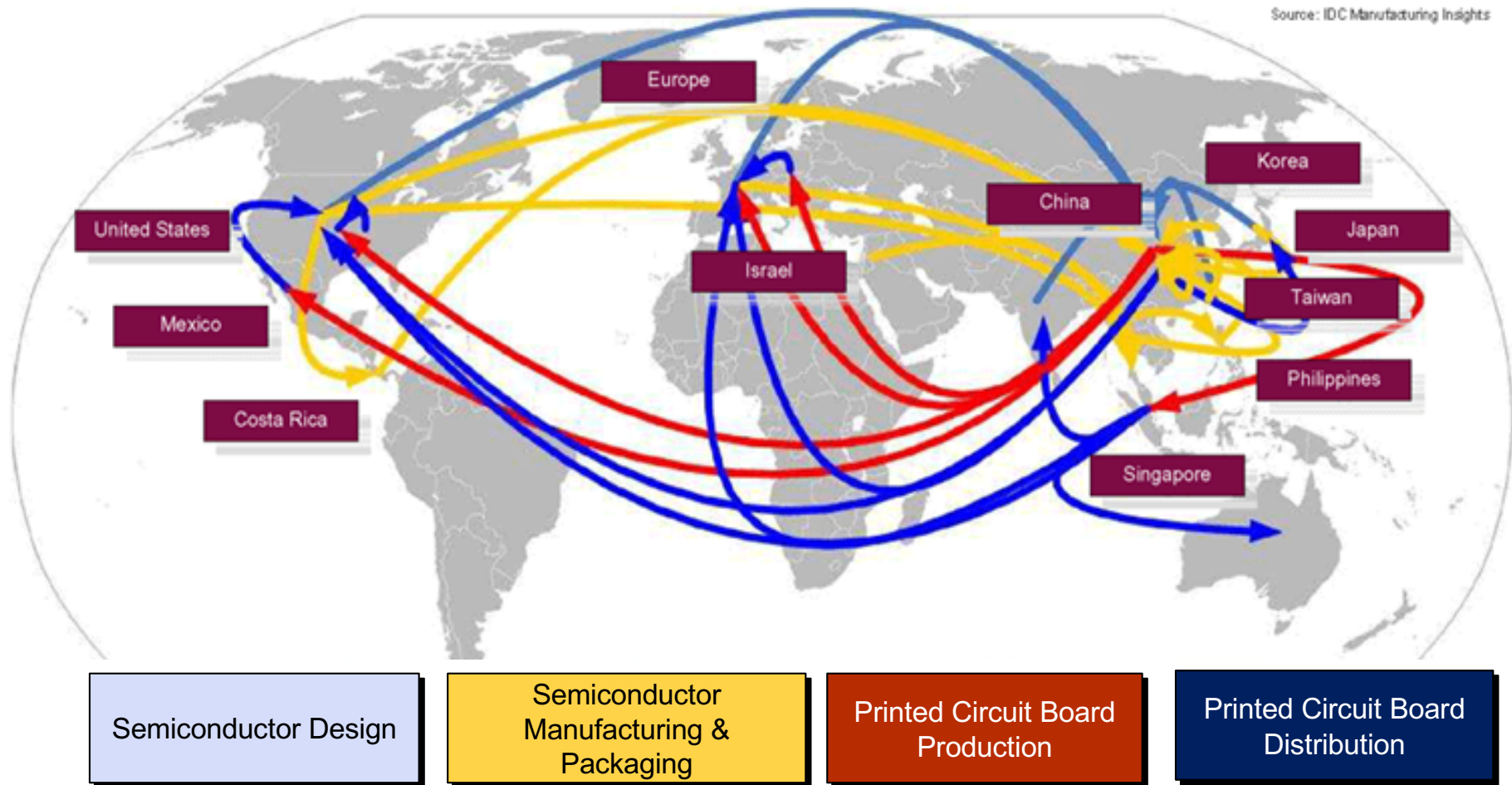


DoD Acquisition Is a Man-made Challenge





The Global Nature of Today's Supply Chains makes chain-of-custody unworkable



Source: IDC Manufacturing Insights & Booz Allen analysis

Lifecycle for a single Joint Strike Fighter component,
which changes hands 15 times before final installation



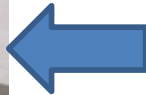
US Electronic Waste is a Contributing Factor



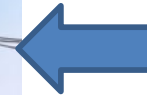
Received in
Developing Country



Removed from
boards and sorted



Shipping from/to U.S.



Resold



Repackaged



Refurbished and remarked



All images courtesy of SMT Corporation



Effects on quality and reliability

Uncontrolled heating during part removal can cause die cracks or delamination, **leading to immediate or latent failures.**



Mishandling or sanding of parts **can cause latent Electrostatic Discharge (ESD) failures.**



Image courtesy of SMT Corporation

Image courtesy of Basel Action Network



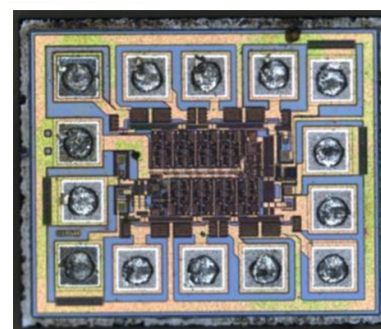
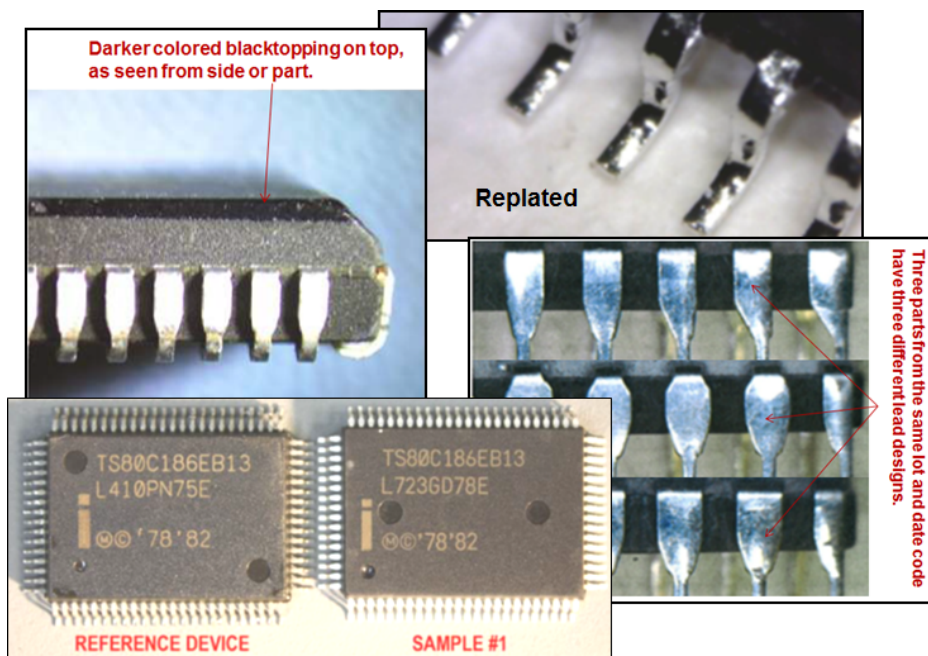
Counterfeits vs Clones

A counterfeit part is manufactured by the OEM and presented as new, but the performance and reliability of the part is questionable:

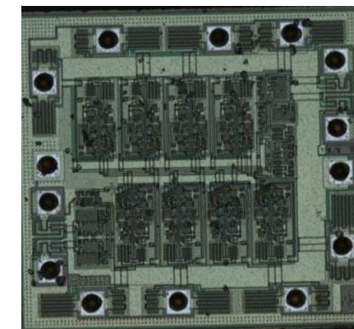
- Used components recycled/remarked
- OEM test failures
- Unlicensed fab overproduction

A cloned part is not manufactured by the OEM but may be designed to mimic the performance of the authentic part:

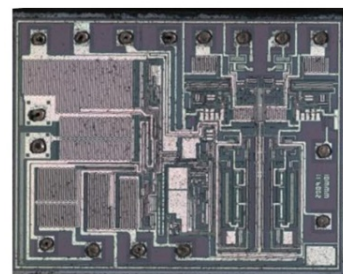
- Copies manufactured in foreign plant
- New design of reverse-engineered components using stolen IP, potentially with altered function



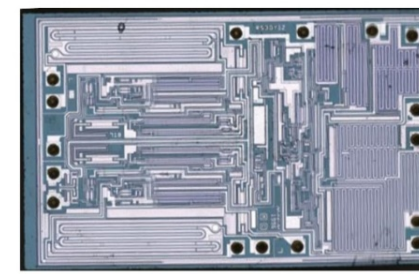
Suspect



Good



Suspect



Good

All images courtesy of NSWC Crane

Distribution A, Approved for Unlimited Distribution

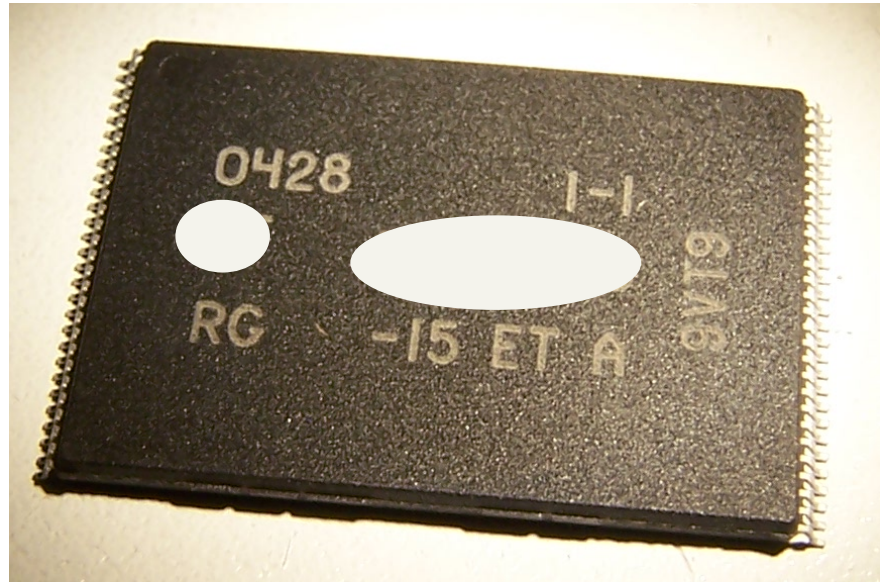


Counterfeits, Clones, Trojans

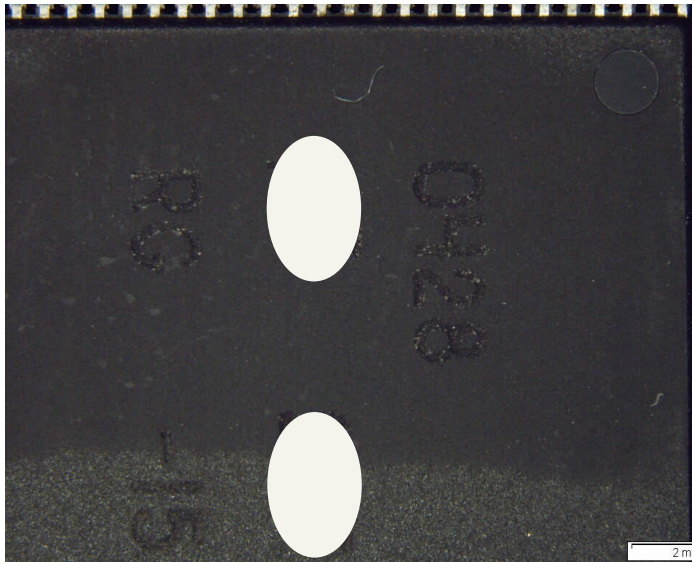


Things are Not Always as They Appear!

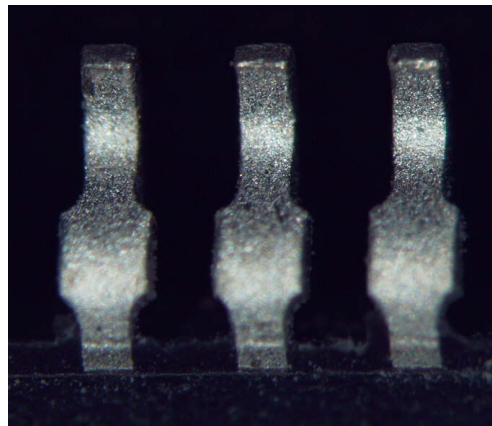
This part looks pretty good, right????



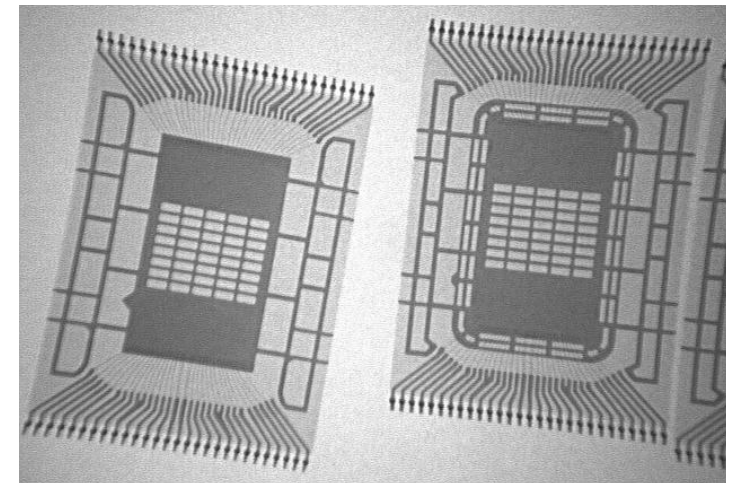
Source:
Images NSW
Crane



**Blacktopped – After
Dynasolve Soak**



Re-Plated Leads



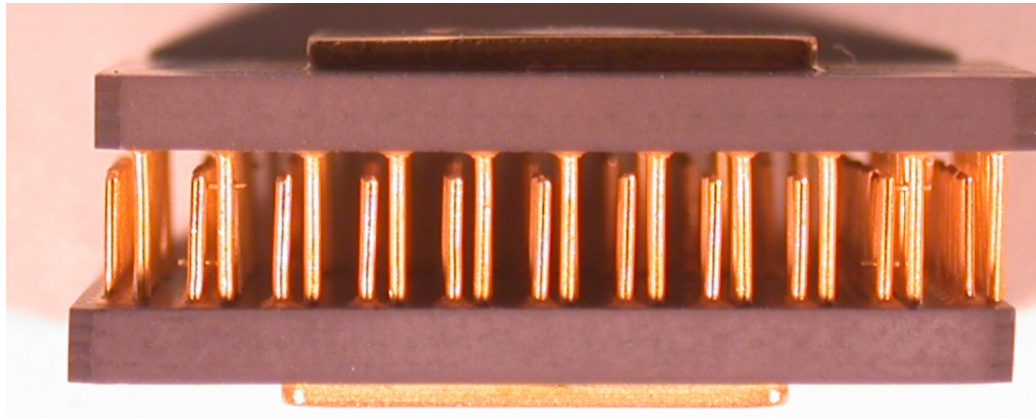
**Different Lead Frames
in Same Lot**



Physical and Optical Inspection is Time Consuming, Labor Intensive, Thus Expensive!



Trimmed (wedge) vs. Untrimmed (flat) Leads



One Part has Trimmed Leads (Shorter than Legitimate Part)



Scratched Window from Sanding and Corroded Metal

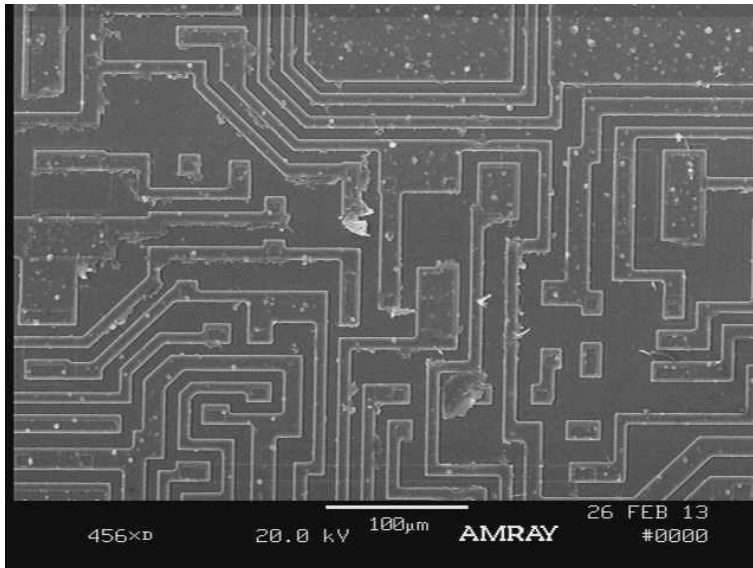
Source: Images NSW Crane

Distribution A, Approved for Unlimited Distribution

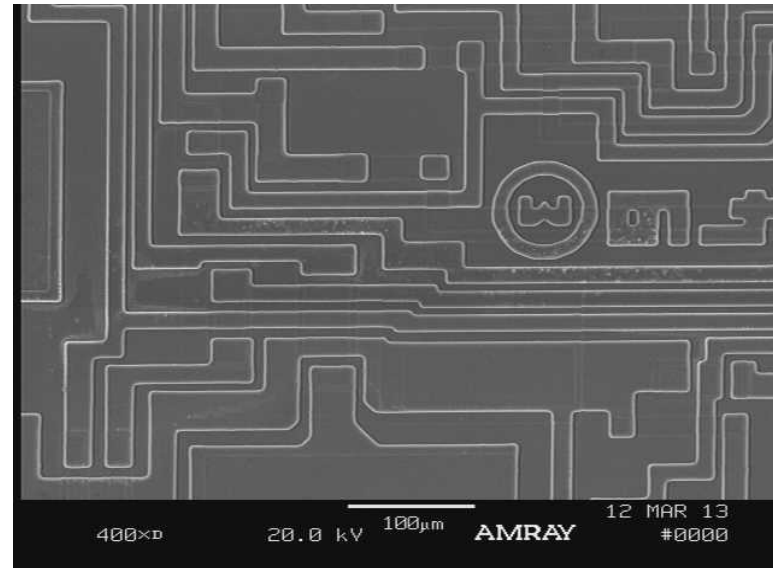
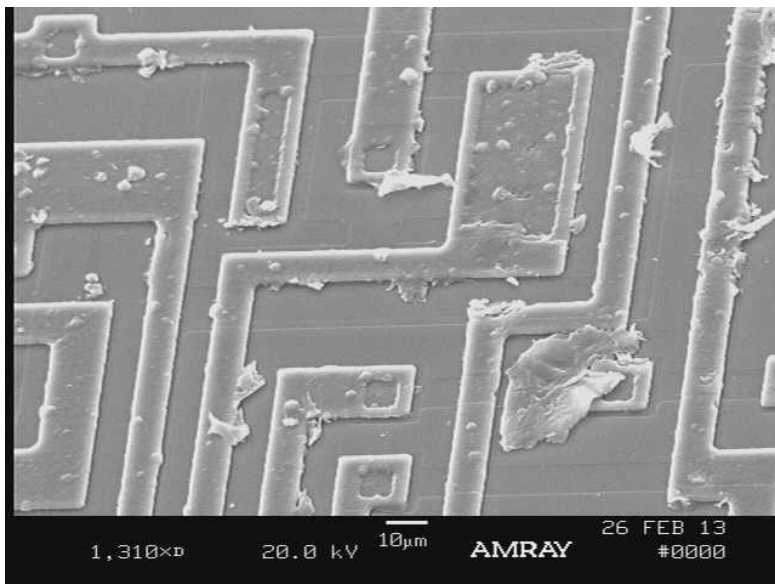


Poor Quality Integrated Circuits

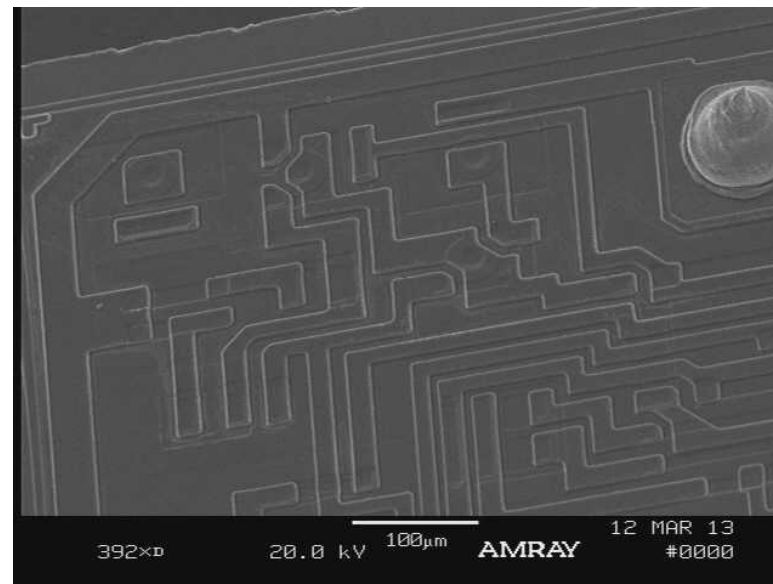
Low quality manufacturing process



Example of Poor Quality



Good Part



Source:
Images NSWC
Crane



Open Source Hardware Trojan Research

Stealthy Dopant-Level Hardware Trojans¹

Abstract. ".....In this paper we propose an extremely stealthy approach for implementing hardware Trojans below the gate level, and we evaluate their impact on the security of the target device. Instead of adding additional circuitry to the target design, we insert our hardware Trojans by changing the dopant polarity of existing transistors. Since the modified circuit appears legitimate on all wiring layers (including all metal and polysilicon), **our family of Trojans is resistant to most detection techniques**, including fine-grain optical inspection and checking against "golden chips"....."

¹Source: Georg T. Becker¹, Francesco Regazzoni², Christof Paar^{1,3}, and Wayne P. Burleson¹

¹University of Massachusetts Amherst, USA

²TU Delft, The Netherlands and ALaRI - University of Lugano, Switzerland

³Horst Görtz Institut for IT-Security, Ruhr-Universität Bochum, Germany

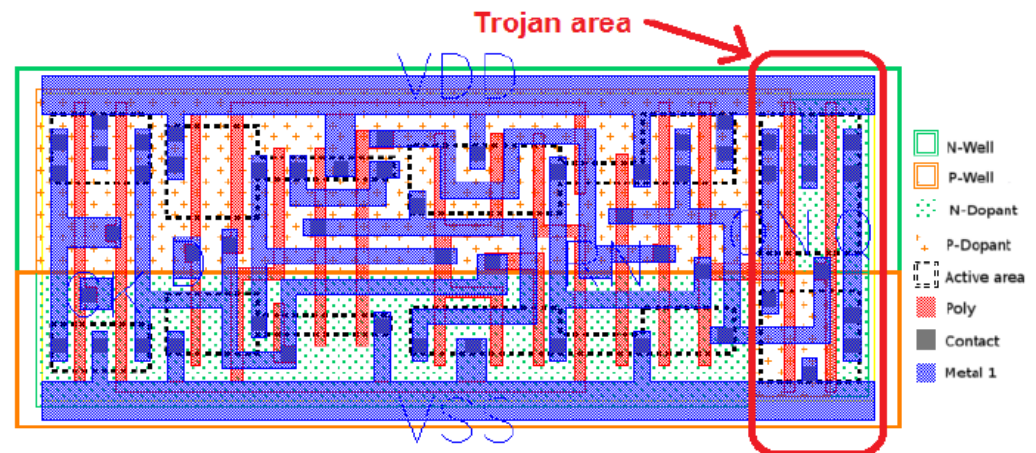


Fig. 2. Layout of the Trojan DFFR_X1 gate. The gate is only modified in the highlighted area by changing the dopant mask. The resulting Trojan gate has an output of $Q = V_{DD}$ and $QN = GND$.

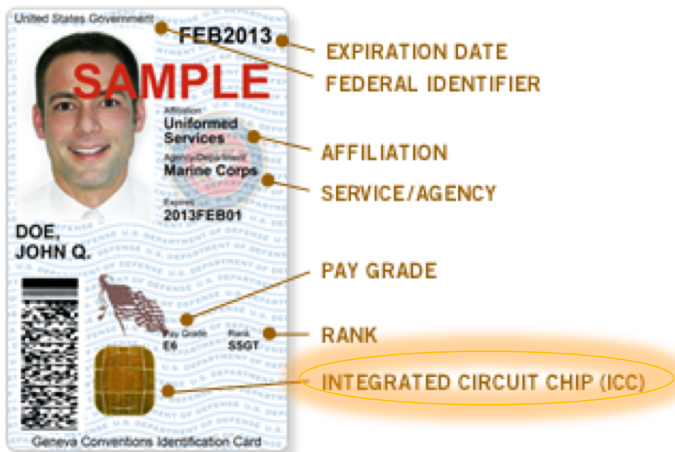


SHIELD Overview



A Hardware Root of Trust for Integrated Circuits

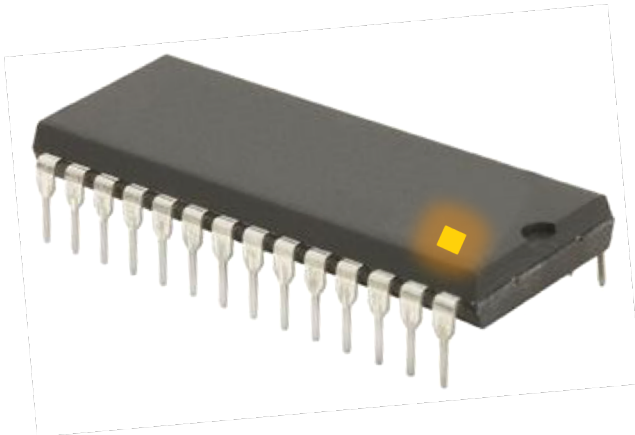
Apply RFID chip concept...



Common Access Card

- PIN (known only to card holder)
- ID Certificates

...to integrated circuit integrity

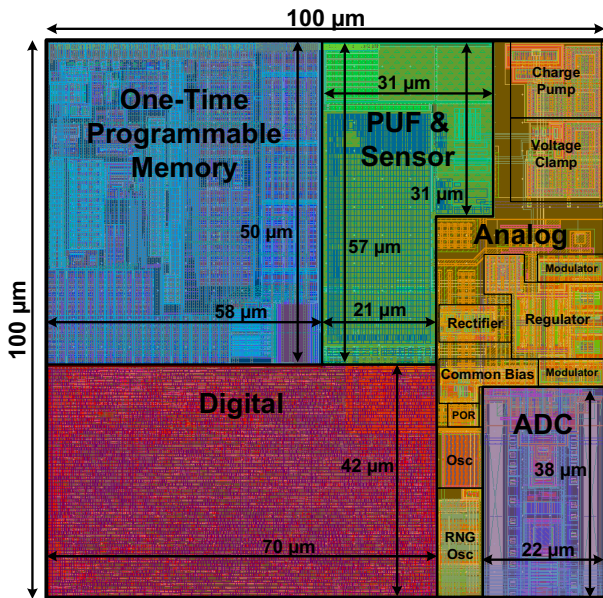


SHIELD Dielet

- Onboard encryption engine with secret key
- Serial ID



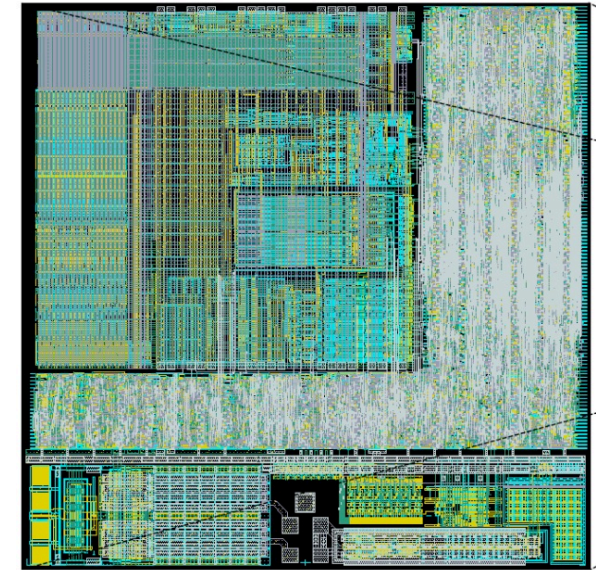
SHIELD – The DARPA Supply Chain Solution



Dielet floorplan (Northrop Grumman)
14nm CMOS

Key SHIELD Specifications

- Unique Key Storage
- Full 256-bit AES encryption engine
- Unpowered, passive intrusion sensors
- RF power and communication
- Transfer fragility
- 100µm x 100µm
- 50 µW Total Power
- Operating temp < 120°C
- Cost < \$0.01 per dielet



Prototype dielet layout (SRI)
28nm CMOS

Asymmetric Security

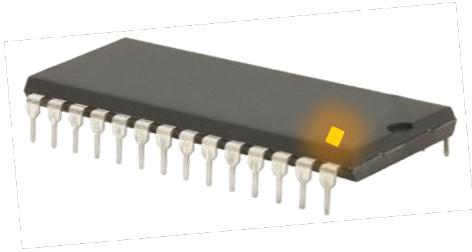
- Non-resettable, “always on” intrusion sensors on dielet
- On-board encryption symmetric key that cannot be “coaxed” from dielet
- ID and Key are unique to the individual host IC (not just the part number)
- Interrogation history (date, time, location) stored on secure server
- Built-in fragility structures kill dielet if removal from host is attempted

SHIELD makes counterfeiting too expensive and too hard to do.



SHIELD Key Components

Dielet



Programmed on-reticle after manufacture

Installed on or within host IC package

- Embedded within package
- Custom package
- Epoxy to surface

No impact to host IC performance or reliability

Reader



Transmits at 5.8GHz to power dielet; 3.6GHz for data transfer

USB connection to smartphone, tablet or computer

Can be configured for high-volume interrogation (transaction time < 1 sec)

Remote Server



Communicates with reader via Internet connection; performs using Amazon and Microsoft web services

Maintains a record for each IC

- Manufacture date
- Part/package information
- Interrogation history



SHIELD Concept of Operation



1. Interrogate dielet on host IC



SHIELD Concept of Operation



2. Unique ID returned by host IC;
reader sends ID to server

FAIL if no response from host IC



SHIELD Concept of Operation



3. Server sends unencrypted challenge to reader; reader forwards challenge to host IC

FAIL on discrepancy between server record and user visual ID
(example: user is testing microcontroller, but server reports ID belongs to an FPGA)



SHIELD Concept of Operation

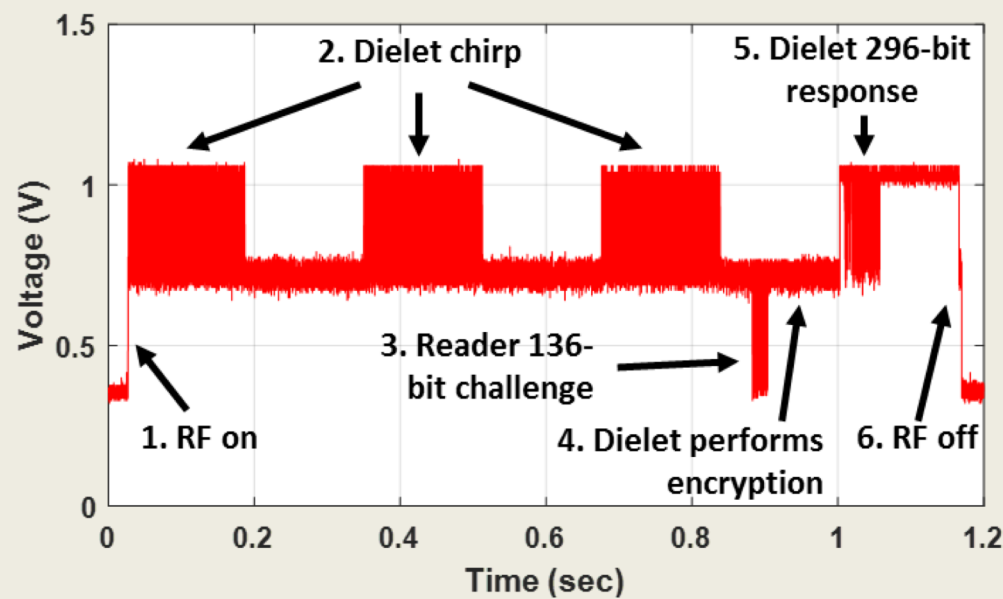


4. Host IC sends encrypted response and sensor status; reader forwards to server

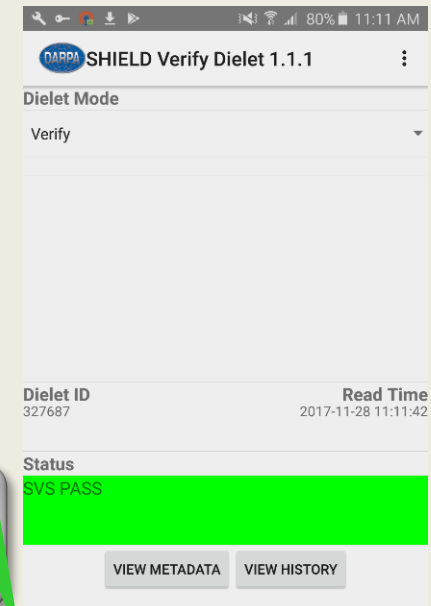
PASS if challenge/response match
FAIL if challenge/response do not match



A SHIELD Authentication Transaction



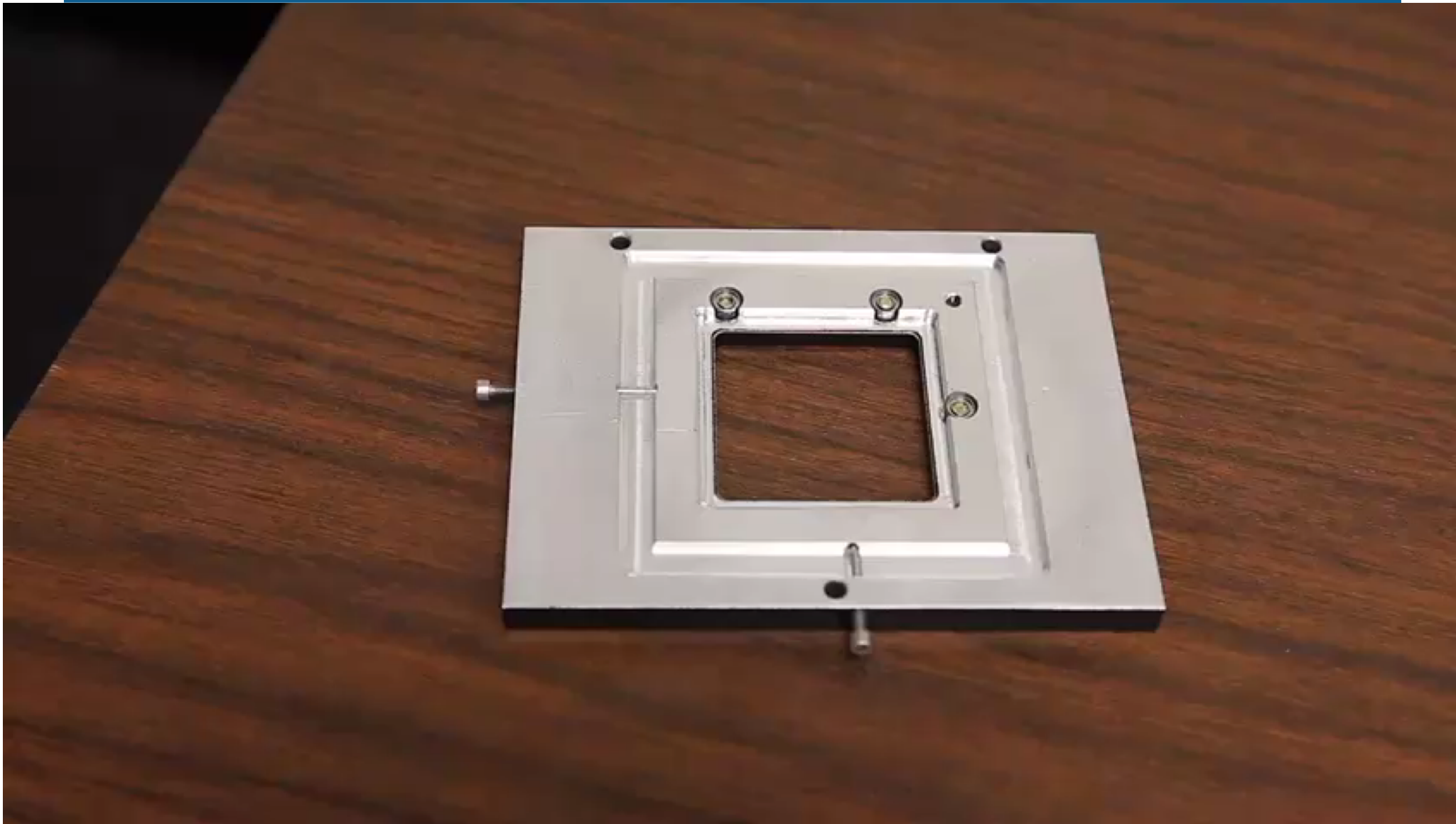
PASS!



A complete SHIELD authentication transaction, including internet latency, takes only 1-2 seconds.



SRI International SHIELD Demo with Reader





SHIELD Program Structure and Performers



SHIELD Program Structure

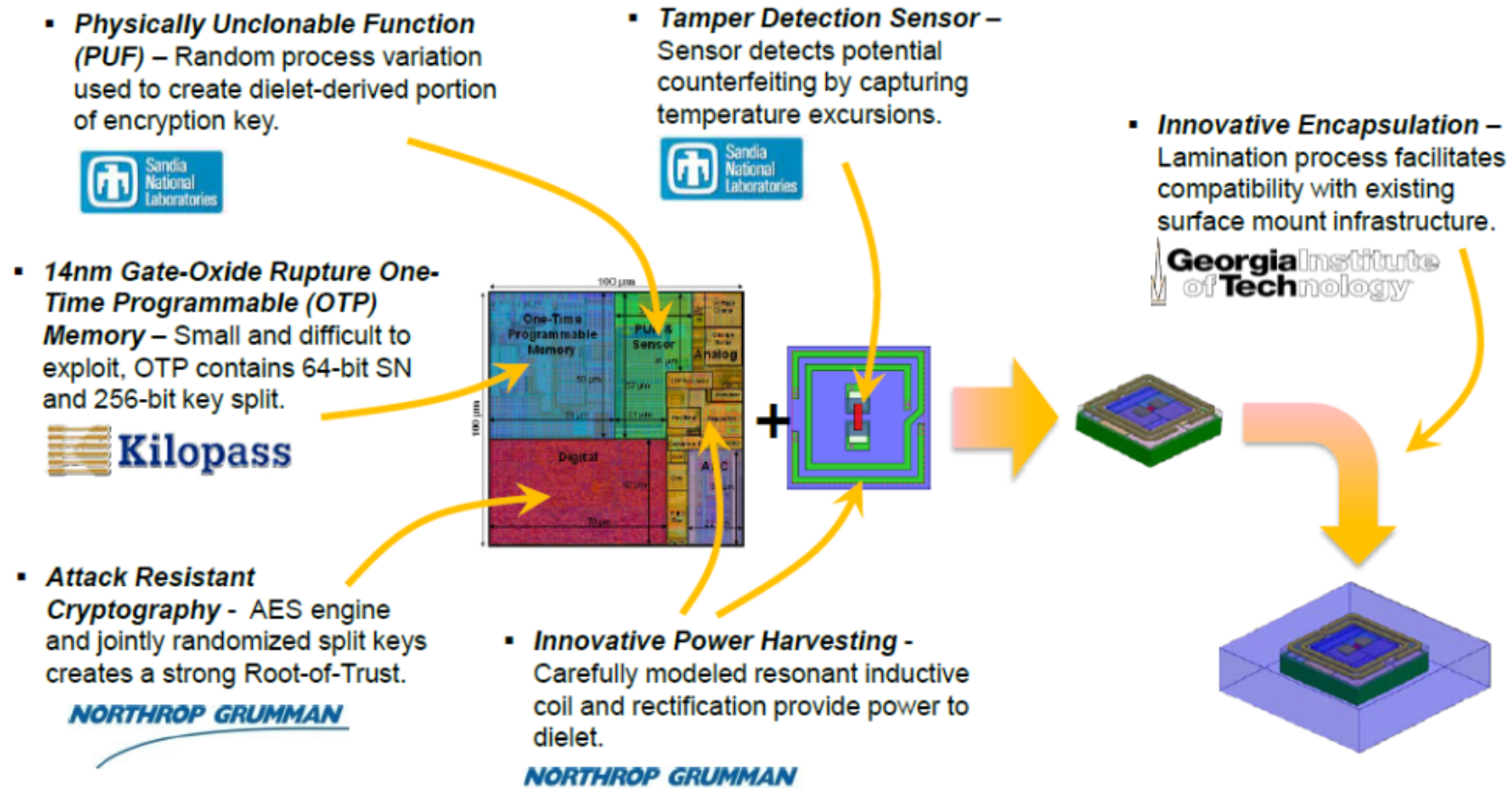
- Program start: January 2015
- Performers:
 - Northrop Grumman (full SHIELD design)
 - SRI International (full SHIELD design)
 - Draper (sensors, fragility)
 - University of California, Berkeley (dielet power/communication, fragility)
 - University of Illinois/Carnegie Mellon University (dielet power/communication)
- Four year program in three phases
 - Phase 1: Technology Development (1.5 years)
 - Phase 2: Hardware Design (1.5 years)
 - Phase 3: Demonstrate the CONOP (1 year)



A Root-of-Trust Prohibitively Difficult to Exploit With Key Protection, Attack Resistant AES, and Smallest OTP

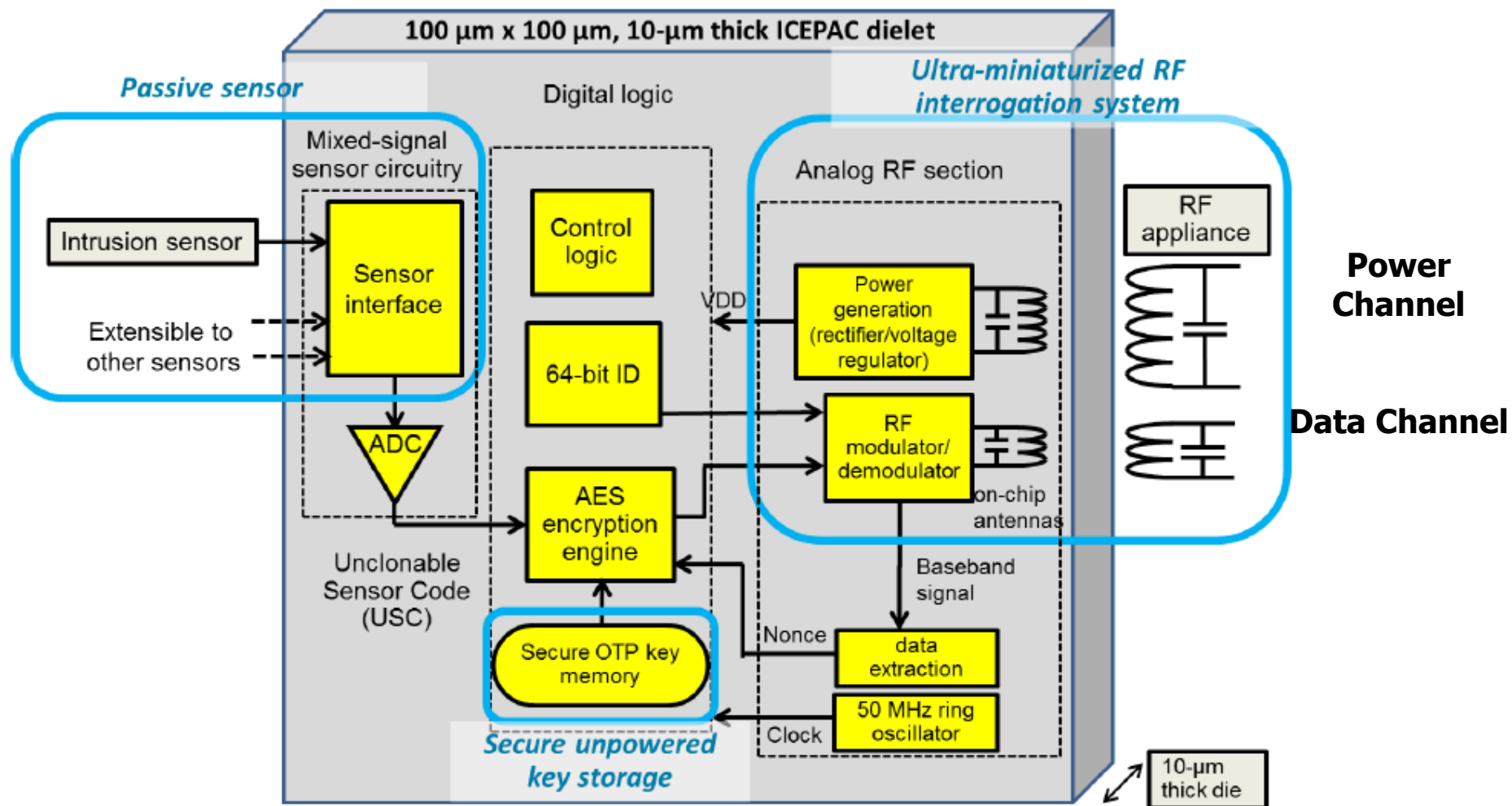
Advancing a Proven AT Tech Base Assessed to Defeat Advanced Threats

NORTHROP GRUMMAN





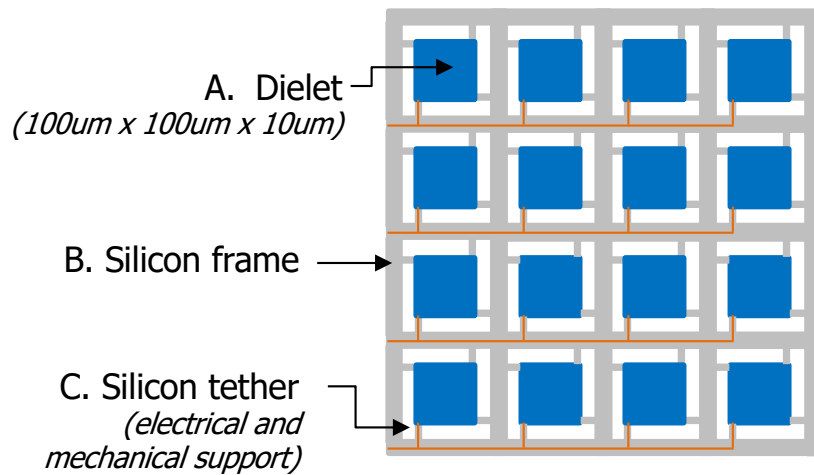
SHIELD Dielet Block Diagram



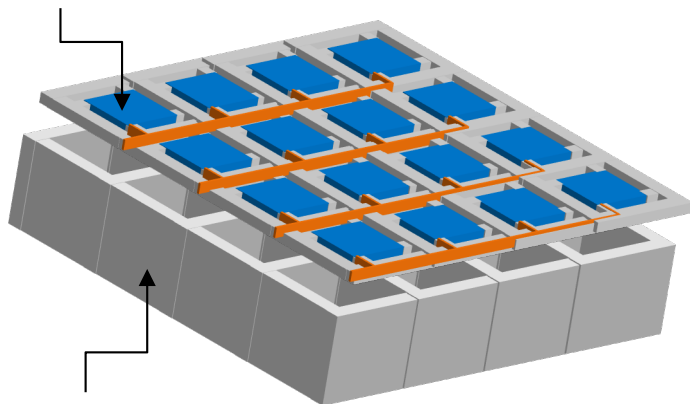


Draper Fragility Summary

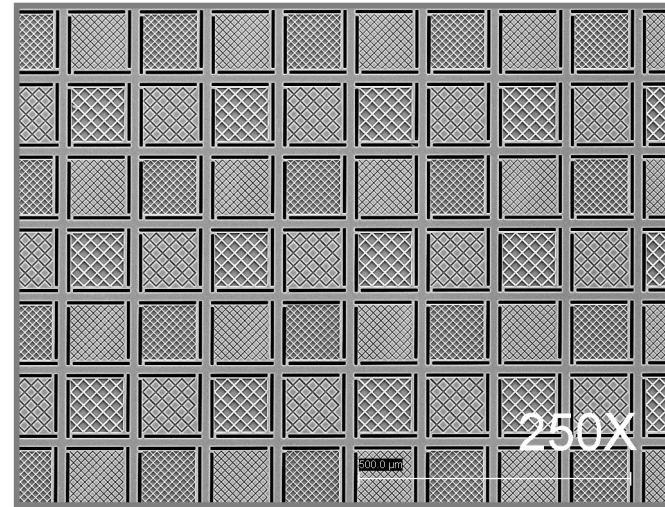
Goal: design and develop a high-yield, low cost architecture for the fabrication, testing, and packaging of ultra-thin ($<10\mu\text{m}$) dielets with engineered fragility



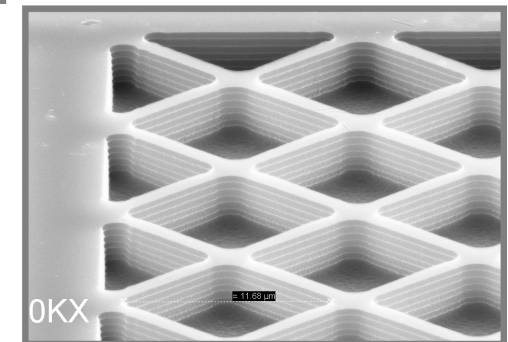
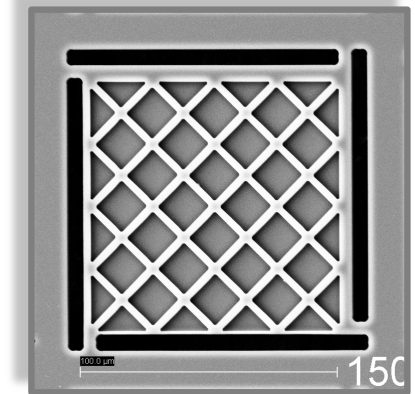
Released dielets anchored to a silicon frame



Carrier wafer with etched cavities under individual dielets



Top View (1,500x)



Perspective View (10,000x)

Key Features

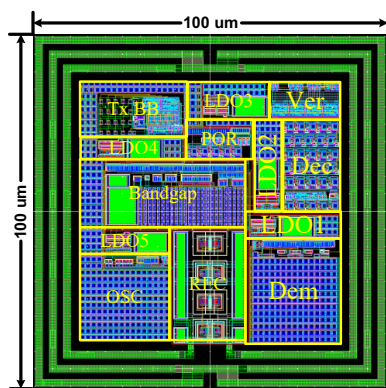
- CMOS compatible architecture with high-yield backend processing
- Higher die count (lower cost) compared to dicing processes
- Strategically placed microstructures to aid in fragmentation

G. Perlin, et al.

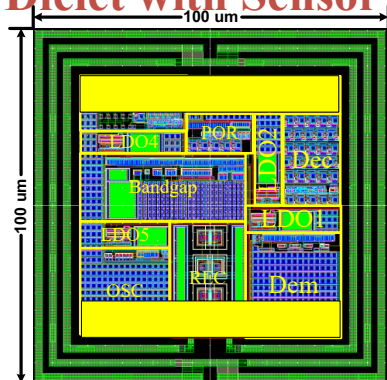


65nm CMOS SHIELD "Technology Vehicle"

2016/5 Tapeout
Standalone Dielet

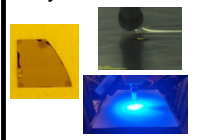


2016/12 Tapeout
Dielet with Sensor

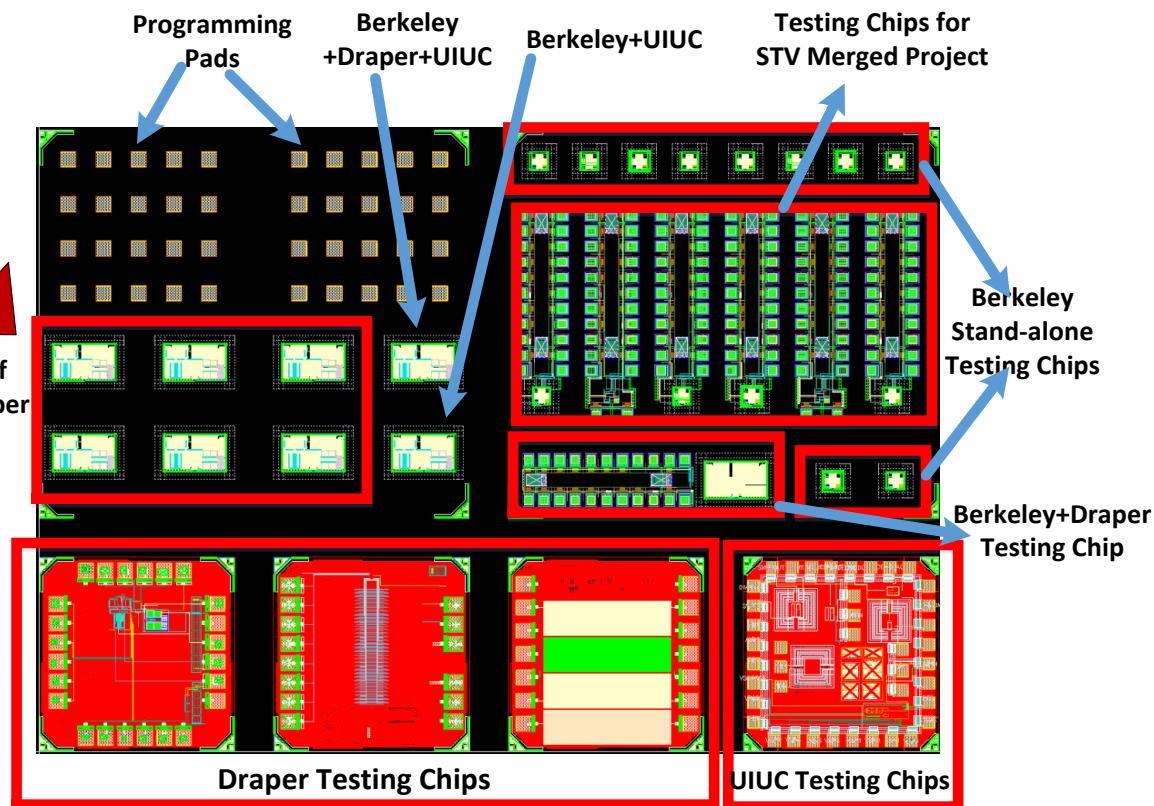


Sensor

Temperature Sensor
UV Sensor
X-ray Sensor



2017/3 Tapeout
STV Merged Project





www.darpa.mil